

LabMaster 10 Zi-A High Bandwidth Modular Oscilloscopes 20 GHz - 100 GHz



Key Features

- Up to 100 GHz Industry leading analog bandwidth
- Acquisition module configurations with up to:
 - 4 channels at 36 GHz
 - 2 channels at 65 GHz
 - 1 channel at 100 GHz
- Up to 240 GS/s sample rate
- Long Memory Up to 1.5 Gpt/ch
- Modular Design build a system with up to 20 acquisition modules, providing:
 - 80 channels at 36 GHz
 - 40 channels at 65 GHz
 - 20 channels at 100 GHz
- ChannelSync™ Architecture for 130 fs matching between channels
- Multi-Lane eye, Jitter and Noise Analysis with SDAIII-CompleteLinQ
- Optical Modulation Analysis with Optical-LinQ
- PAM4 Eye, Jitter and Noise Measurements with PAM4 Signal Analysis
- Industry's only true hardware
 14.1 Gb/s serial trigger

The LabMaster 10 Zi-A series of real-time oscilloscopes boasts the world's highest bandwidth and fastest sampling rate at 100 GHz and 240 GS/s. This world-leading performance is key to acquiring, analyzing and understanding the fastest phenomena found in R&D labs, where engineers are working on next-generation communication systems, high bandwidth electrical components and fundamental scientific research.

The Fastest Oscilloscope for the Most Demanding Signals

Whether working on communications technology capable of terabit/s symbol rates, analyzing the quickest and most energetic laser pulses, or building links using high speed NRZ or PAM4 technologies, the LabMaster 10 Zi-A is the ideal tool for acquiring, displaying and analyzing the highest-bandwidth electrical signals.

For more channels at the highest bandwidths, multiple LabMaster acquisition modules can be combined with one Master Control Module to build a system of up to 80 channels at 36 GHz, 40 channels at 65 GHz, or even 20 channels at 100 GHz. ChannelSync technology ensures precise timing synchronization by design - channel-to-channel jitter of only 130 fs exceeds the performance of "single-box" systems.

Sophisticated Software for Sophisticated Analysis

The LabMaster 10 Zi-A Series offers an extensive set of standard math tools and add-on software packages that integrate seamlessly into the oscilloscope "MAUI" interface. LabMaster 10 Zi-A oscilloscopes excel at performing in-depth analysis of complicated signals. For NRZ signals, the SDAIII-CompleteLinQ package compares eye, jitter and noise on up to four lanes, simultaneously. The Optical-LinQ package simplifies analysis of coherent optical signals such as DP-QPSK and DP-16QAM. PAM4 Signal Analysis enables the industry's only true eye, jitter and noise measurements on PAM4 signals. Since leading-edge technologies often require custom analysis, LabMaster 10 Zi-A also comes standard with the ability to run MATLAB scripts in-stream.

World's Highest Bandwidth Real-Time Oscilloscope

The LabMaster 10 Zi-A modular oscilloscope breaks bandwidth, sample rate, and channel count barriers, providing more "bandwidth density" than any other oscilloscope. Its modular design provides the simplest upgrade path in bandwidth and number of channels. In one acquisition module, it provides four channels at 36 GHz with the ability to expand to 20 modules, for 80 channels of simultaneous acquisition.

Performance across multiple modules is guaranteed with ChannelSync, which ensures precise synchronization of all channels in all acquisition modules using a single distributed 10 GHz clock and a single trigger circuit. Synchronization is identical to that provided with a single oscilloscope, <130fs_{rms} jitter between all channels.

The modular design means the LabMaster 10 Zi-A is future proof and upgrading is easy. Start with one acquisition module and add more channels or higher bandwidth modules later as needed.

No bitrate or symbol rate is too high for the LabMaster 10 Zi-A, with its industry-leading bandwidth and sample rate. LabMaster 10 Zi-A is perfect for 10-16 Gb/s technologies such as 40/100 GBASE-R Ethernet, SAS12, and PCI Express Gen4 that benefit from 80 GS/s on four or more channels at up to 36 GHz. Ultra-high speed technologies, such as CEI-25/28, CEI-56, and coherent optical formats including DP-QPSK, 16-QAM, MIMO benefit from 65 or 100 GHz bandwidths and four or more channels.



A LabMaster 10 Zi-A oscilloscope that provides one channel at 100 GHz, one channel at 65 GHz and four channels at 36 GHz



Add up to twenty acquisition modules for 20 channels at 100 GHz, 40 channels at 65 GHz or 80 channels at 36 GHz.

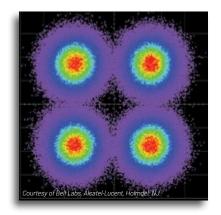
- World's Highest Performing Real-Time Oscilloscope 100 GHz bandwidth, (3.5 ps risetime_{20 – 80%}), 240 GS/s sample rate, up to 1.5 Gpts of analysis memory
- 2. Modular start with four channels and grow the system over time.
- **3.** Wide bandwidth upgrade range from 20 to 100 GHz provides long-term investment protection
- **4.** ChannelSync architecture utilizes a 10 GHz distributed clock for precise alignment of all acquisition systems
- 5. Single trigger circuit for all modules eliminates additive trigger jitter that occurs with 10 MHz clocking and trigger synchronization of multiple conventional oscilloscopes
- 6. Simple modular setup, just connect and acquire signals.
- 325 MB/s data transfer rate from the LabMaster to a separate PC with Teledyne LeCroy Serial Interface Bus (LSIB) option
- 8. Server-class multi-core processor combines with X-Stream II streaming architecture for fast acquisition and analysis — 20 cores of processing power and 32 GB of RAM standard, expandable to 192 GB
- 9. Utilize the built-in 15.3" widescreen (16 x 9) high resolution WXGA color touch screen display or connect a monitor with up to WQXGA 2560 x 1600 pixel resolution
- Highly stable timebase (50fs_{rms}) for ultra-low intrinsic jitter, enabling low Jitter Measurement Floor even over long acquisitions.
- **11.** Deepest standard toolbox with more measurements, more math, more power
- 12. Eye Doctor™ II and Virtual Probe Signal Integrity Toolsets provide real-time de-embedding, emulation, and equalization on serial data channels
- **13.** Up to 14.1 Gb/s Serial Trigger available 80-bit NRZ, 8b/10b and 64b/66b symbol triggering

FASTEST DIGITIZER FOR THE FASTEST SIGNALS

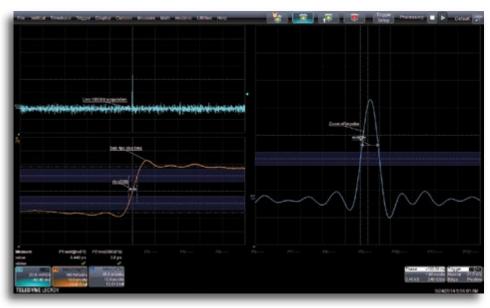
For over 30 years, Teledyne LeCroy has consistently shown industry leadership by pushing forward the limits of oscilloscope performance and waveshape analysis. The LabMaster 10 Zi-A continues this tradition of engineering excellence, incorporating custom chip design and patented innovations to reach unprecedented digitization performance: 100 GHz bandwidth and 240 GS/s sample rate.

Capturing and Characterizing the Fastest Phenomena

Scientific research of phenomena that occur at the shortest timescales require the fastest digitization speeds. At 240 GS/s, samples are acquired at time intervals of 4.17 ps, 50% faster than the next-fastest digitizer, yielding excellent signal reconstruction. For applications and experiments requiring multiple channels, the patented ChannelSync architecture



I & Q components from 160 GBaud QPSK signals are captured by a two-channel LabMaster 10-100Zi-A oscilloscope.

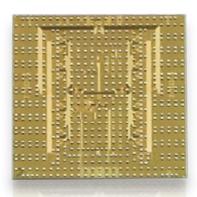


Acquisition and analysis of femtosecond laser pulse by LabMaster 10-100Zi-A.

provides unrivaled matching between channels: less than 130 fs channel-to-channel jitter. Such precision is not possible with conventional methods of synchronizing two independent oscilloscopes. This synchronization is key for applications requiring closely matched channels, such as optical modulation analysis.

Custom Chip Design

The LabMaster 10 Zi-A acquisition system utilizes multiple custom monolithic ICs, including designs for the track & hold, analog-to-digital converters and fast acquisition memory. These designs are at the heart of our industry-leading 4 channel 36 GHz, 80 GS/s design. No other 4-channel oscilloscope on the market achieves 36 GHz bandwidth.



Digital Bandwidth Interleaving

Digital Bandwidth Interleaving uses high-precision diplexers and mixers to split the input signal into separate 36 GHz bands for digitization, and recombines them to achieve record breaking bandwidths. DBI technology, first used in 2005, is now in its 8th generation in the LabMaster 10-100Zi-A, where it is almost triples the 36 GHz ADC bandwidth to 100 GHz. In the LabMaster 10-65Zi-A, DBI is used in a doubler configuration to achieve 65 GHz bandwidth.

ENABLING HIGH-SPEED SERDES DEVELOPMENTS

LabMaster 10 Zi-A is uniquely suited to the demands of highspeed SerDes characterization. For differential signalling requirements, the LabMaster 10-65Zi-A provides two channels at 65 GHz. and accurately characterizes 28 - 32 Gb/s signals. Oscilloscope risetime_{20 - 80%} is an impressive 4.9 ps, a necessary speed when the unit interval (UI) is a mere 36 ps wide (or less). The 1024 Mpts/Ch acquisition memory provides the ability to capture very long waveforms, permitting deterministic jitter (Dj) decomposition on long patterns - something not possible in a sampling oscilloscope. Two input channels provides the ability to input a differential signal pair into the oscilloscope, eliminating the bandwidth, noise, and accuracy constraints inherent in a separate, external differential amplifier.

Multiple Configurations Provide Flexibility

In addition to 2 channels at 65 GHz. a LabMaster 10-65Zi-A system will also provide 4 channels at 36 GHz for testing and debugging of multiple lanes at lower bandwidth. This can be especially useful for crosstalk analysis or lane skew testing when multiple lanes are deployed. Thus, a 65 GHz LabMaster can deployed in a variety of ways and serve many important application needs in the same lab. For the fastest digitization possible, use the 100 GHz LabMaster 10-100Zi-A acquisition module. Multiple MCM-Zi-A Master Control Modules and Acquisition Modules can even be mixed and matched as needs change.

Superior Serial Data/Crosstalk Analysis and Debug Tools

Teledyne LeCroy's SDAIII-CompleteLinQ Serial Data and Crosstalk Analysis products provide unique capability to simultaneously calculate, display and compare eye diagrams, jitter and noise measurements from four separate lanes or one lane probed or modeled in four different locations. EyeDoctorII and VirtualProbe tools use S-parameters to de-embed/emulate fixtures and interconnects and show you the signal where you can't put a probe. Use the optional 14.1 Gb/s true-hardware serial trigger for capturing rare events. A variety of serial decode annotations are available for common encoding schemes, as well as serial protocols. Teledyne LeCroy's combination of serial decoders and ProtoSync™ protocol analysis views permits link layer debugging on initial SerDes transmissions before protocol analyzer hardware is typically available.



WORLD'S LEADING OPTICAL MODULATION ANALYZER

LabMaster 10 Zi-A combines
the world's fastest real-time
bandwidth and four input
channels with pristine signal
fidelity to meet the advanced
research and development
requirements for optical coherent
modulation analysis on long-haul
telecommunication systems.

The World's Leading Optical Modulation Analyzer (OMA)

The LabMaster 10Zi-A is a key component of the world's highest-performance OMA solution. Teledyne LeCroy have teamed up with Coherent Solutions Ltd to provide the other half of the solution. The IQS Series Coherent Optical Receiver is seamlessly integrated and controlled by Optical-LinQ analysis software, providing the most powerful and flexible OMA solution on the market.

Premiere Performance

No other OMA on the market delivers the performance of the Teledyne LeCroy / Coherent Solutions OMA.

DP-QPSK signals with baud rates up to 130 GBaud are detectable by integrating an industry leading coherent receiver (with 70 GHz electrical bandwidth) with a 4-channel LabMaster 10-65Zi-A oscilloscope.

The analyzer runs the Optical-LinQ software package, which includes all of the software tools and DSP algorithms to completely characterize the optical signal under test.



LabMaster 10-65Zi-A and IQS70 70 GHz Coherent Optical Receiver

OMA system bandwidth: 65 GHz Max detectable baud rate: 130 GBaud



LabMaster 10-36Zi-A and IQS42 42 GHz Coherent Optical Receiver

OMA system bandwidth: 36 GHz Max detectable baud rate: 72 Gbaud

IQS Series Coherent Optical Receiver

- Up to 70 GHz electrical outputs for X & Y polarization of I & Q signals.
- Built in LO, C and/or L band
- Laser wavelength/frequency and power adjustable via Optical-LinQ or front panel



COMPLETE ANALYSIS WITH OPTICAL-LINQ

The Optical-LinQ software package performs optical modulation analysis when using either the integrated IQS-series receiver or other coherent receiver.

Extensive set of analysis tools

The Optical-LinQ software from Coherent Solutions includes an extensive selection of visualizations that let users gain a complete understanding of the quality and impairments in the transmitted optical signal. Visualizations include constellations, trajectories, eye diagrams and tracks, of I, Q, phase EVM, and much more. Parametric measurements include EVM%, I & Q Bias Error, Quad Error, IQ Skew and offset. See the OMA brochure for complete information.

True BER analysis

Optical-LINQ offers both quick and convenient BER Estimates along with true and accurate BER counting capabilities. The BER set up panel allows the configuration of the coding scheme from one of the common preset options, or any custom-defined bit sequence and multiplex options.



Analysis of a DP-QPSK optical signal.

Use Built-in or Custom DSP Algorithms

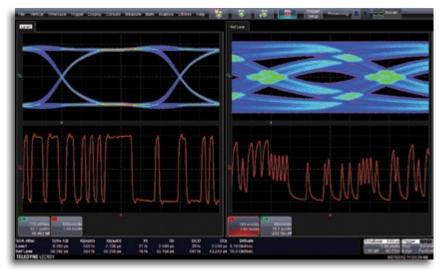
Test and validation of digital signal processing (DSP) algorithms is a vital part of the transceiver development.

Optical-LINQ is equipped with built-in DSP algorithms for polarization de-multiplexing, dispersion compensation and carrier recovery such as CMA, MMA, and Viterbi & Viterbi to use as tested reference algorithms. The custom code integration feature permits validation of custom algorithms in MATLAB format.

Complete Modulation Format Support

Optical-LINQ comes with pre-set support for many of the common optical modulation formats, including QPSK, 16QAM and 64QAM. If you are developing or working with non-conventional modulation formats, you can define your own format using Optical-LINQ's powerful custom modulation format definition capability

SDAIII-CompleteLinQ SERIAL DATA ANALYSIS PRODUCTS



The Teledyne LeCroy SDAIII-CompleteLinQ Serial Data Analysis products contain multilane eye and jitter analysis, LaneScape™ comparison modes, vertical noise measurements, and crosstalk analysis tools. These capabilities provide the deepest insight into the behavior of multi- or single-lane serial data systems.

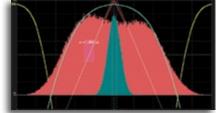
SDAIII Core Toolset

Teledyne LeCroy provides the most complete toolset in the industry for jitter measurements and eye diagram/ jitter analysis. Rj and Dj are separated and Dj is decomposed using one of three dual-Dirac algorithms. Eye diagrams containing all acquired unit intervals are rendered 10-100x faster than competitive systems. Eye diagram analysis tools, such as the extrapolated

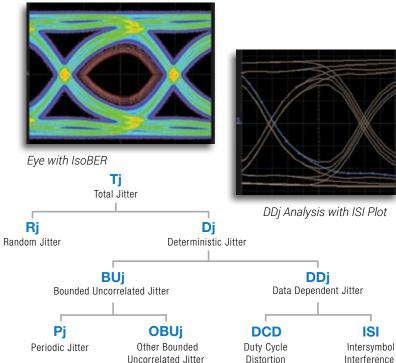
IsoBER plot, aid insight. Multiple additional tools. such as Tracks. Histograms, and Spectrum waveforms. enhance the understanding of jitter causes.

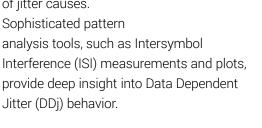
Sophisticated pattern

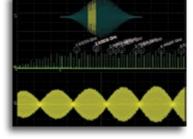
Jitter (DDj) behavior.



Rj+BUj Analysis







Pj Analysis



Three Jitter Methodologies

Choose from three dual-Dirac models to separate jitter into total, random and deterministic components (Ti, Ri, Di). The Spectral Ri Direct method determines Ri directly from the jitter spectrum, and is the most used algorithm. Spectral Rj+Dj CDF Fit follows the FibreChannel MJSQ model. In situations where large amounts of crosstalk/BUj raise the spectral noise floor, the NQ-Scale method will provide more accurate separation of Ri and Di, and therefore more accurate Ti results.

OPTIONAL SDAIII UPGRADES

Measure up to 4 Lanes Simultaneously

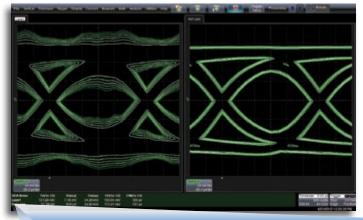
"LinQ" products provide extensive multi-lane analysis capabilities. Quickly understand lane-to-lane differences in jitter measurements, eye diagrams, and jitter analysis. Perform aggressor on/off analysis, and see the results from both scenarios simultaneously. Save the analysis of a particular scenario to the Reference Lane, and configure a LaneScape™ Comparison mode to compare the Reference to either one, two or all lanes. Each "lane" can be a different serial data lane, or a different analysis of data from a single serial data lane - ideal for comparing different equalization schemes (using Eye Doctor II option) or

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examining system behaviors at different locations in the lane (using probes or the VirtualProbe option).

Vertical Noise and Crosstalk

The Crosstalk and CrossLinQ packages provide vertical noise measurements and crosstalk analysis tools for



SDA Noise EH(1e-12) Tn(1e-12) Rn(sp) Dn(sp) EW(1e-12) Lane1 131.28 mV 7.18 mV 34.39 mV 105.04 mV 125 ps 33.38 mV 646 µV Ref Lane 24.93 mV 172.41 mV 131 ps

complete aggressor/victim analysis. Use one of three dual-Dirac models to measure and separate noise into total (Tn), random (Rn) and deterministic (Dn) components, and further decompose Dn into Intersymbol Interference Noise (ISIn) and Periodic Noise (Pn). Only Teledyne LeCroy performs this analysis on real-time oscilloscopes. Similar to jitter analysis, noise can be viewed as a noise track, histogram and spectrum, providing insight into the vertical noise resulting from coupling to other active serial data lanes or other interference sources. The Crosstalk Eye shows the probabilistic extent of noise both inside and outside the eye, quickly showing the impact of excessive noise that is not

possible to see in a traditional eye diagram.

CompleteLinQ Does it All

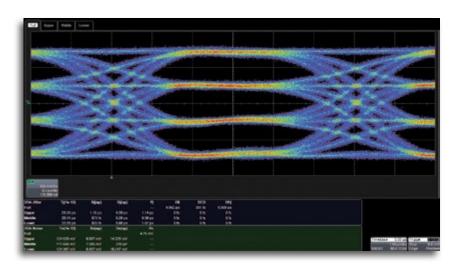
The CompleteLinQ user interface framework provides easy access to all features described above, and also integrates EyeDoctorII and VirtualProbe capabilities for Tx/Rx equalization and fixture/channel de-embedding/emulation. Order SDAIII-CompleteLinQ to equip your oscilloscope with all of Teledyne LeCroy's Serial Data Analysis and Signal Integrity tools.





EYE, JITTER AND NOISE ANALYSIS OF PAM4 SIGNALS

PAM4 signaling is seen as the next step in the evolution of serial data signal formats, allowing two bits of information to be transmitted per UI rather than one. Next generation standards from OIF and IEEE including CEI-56G-VSR and 100GBASE-KP4 utilize PAM4 signaling. Teledyne LeCroy's PAM4 analysis package extends our industry-leading eye, jitter and noise analysis capabilities to perform a complete analysis of all three eye openings in a PAM4 signal.



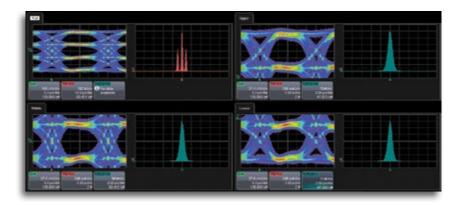
Measure Eye, Jitter and Noise

For each of the three eye openings, the PAM4 software package performs a complete analysis to determine the eye openings, jitter and noise as a function of BER. Measurements for each opening include: Eye Height, Width Tj, Rj, Dj, Tn, Rn and Dn. Mean and RMS vales for each level are also determined, as well as periodic noise and jitter results.

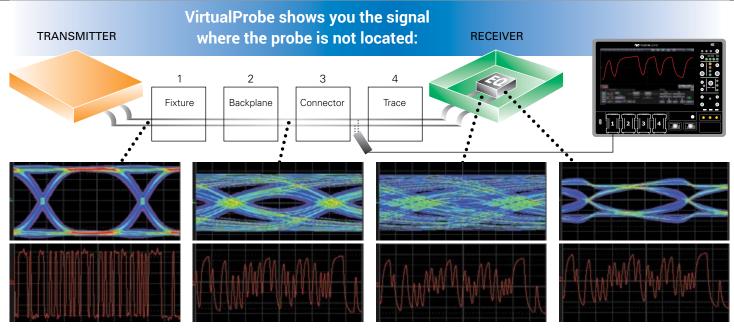


Deeper Understanding with Additional Views of Jitter and Noise

The PAM4 package includes the views of noise and jitter utilized in the SDAIII-CompleteLinQ package. Enhance understanding of jitter and noise by displaying histograms, spectra, bathtub and IsoBER curves for each eye opening. PAM4 analysis is compatible with EyeDoctorII, allowing users to de-embed channel and fixture effects, emulate a channel, or apply equalization.



EYEDOCTOR™II AND VIRTUALPROBE SIGNAL INTEGRITY TOOLS



Virtually probe the signal at the transmitter with the fixture present, and then de-embed its effects form the measurement.

View the signal between structures to understand losses, ISI and crosstalk caused by backplanes, interconnects and connectors.

See what the eye looks like at the receiver - even if it is not in reach of a differential probe.

Use EyeDoctor to open the eye by modeling CTLE, FFE and DFE equalizers used by your receiver.

As signal speeds and data rates continue to rise, signal integrity effects such intersymbol interference (ISI) and crosstalk become more prevalent and challenging. Use Teledyne LeCroy's Advanced Signal Integrity tools to transform your measured signal to include the effects of de-embedding, emulation and equalization algorithms.

De-embed, Equalize and Emulate with EyeDoctorII

Curious to know what your signal would look like without fixture effects? Do you need to understand how ISI and crosstalk of a modeled channel will affect your jitter margin? Or are you seeking to determine which equalization schemes will do the best job of opening a closed eye? The EyeDoctorII package includes easy configuration of basic de-embed/emulation scenarios, CTLE, DFE and FFE equalizers, and transmitter emphasis/de-emphasis.

Advanced De-embedding, Emulation and Virtual Probing

The VirtualProbe package expands the de-embedding and emulation capabilities of EveDoctorII. Configure a multi-block circuit using modeled S-parameters or measured with a Teledyne LeCroy SPARQ (or other VNA), and VirtualProbe will build the transfer function that returns the signal as it would appear before or after any block in the circuit. The electrical behavior of a block to reflect and transmit signals can be included, added or removed in order to de-embed or emulate fixtures or channels. Probe loading effects can also be removed. When used in conjunction with the Crosstalk, CrossLinQ or CompleteLinQ SDAIII options, crosstalk between lanes can be modeled using 8 and 12-port S-parameters. Use the Teledyne LeCroy SPARQ to measure these S-parameters at a fraction of the price of a VNA.

Use EyeDoctorII and VirtualProbe with SDAIII CompleteLinQ products

When using EyeDoctorII and VirtualProbe on oscilloscopes enabled within the SDAIII-CompleteLinQ products, configure de-embedding, emulation and equalization from the same simple flow-chart dialog as all other serial data analysis features. When enabled with the "LinQ" option to enable 4 lanes, users can configure EyeDoctorII and VirtualProbe configurations on each lane, facilitating rapid comparisons of different de-embedding and equalization setups.

Learn More

teledynelecroy.com/dl/1023 teledynelecroy.com/vid/M0T6WEC0JYQ teledynelecroy.com/dl/1216 teledynelecroy.com/dl/1136

MOST COMPLETE DEBUG SOLUTION

Connecting a problem with its root cause often requires viewing the signal in multiple domains. The LabMaster 10 Zi-A allows you to combine multiple analysis types into a single, correlated display:

- Analog signals
- Protocol decodes
- Eye diagrams
- Jitter and noise breakdown
- Measurement parameters
- Frequency-domain traces

Serial Decode—A Whole New Meaning to Insight

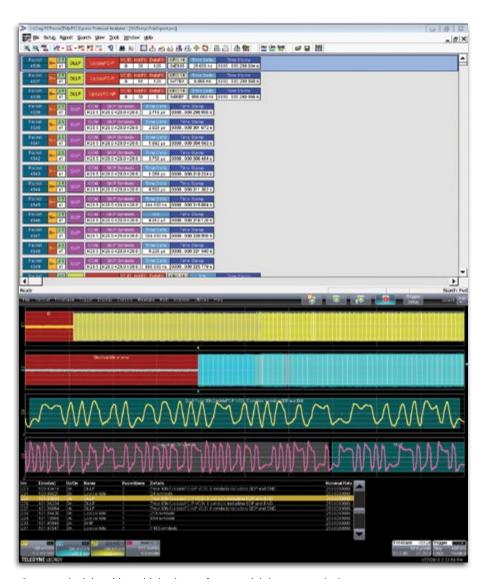
Over 19 different protocols are supported with serial decoders. Use ProtoSync with PCIe, USB, SATA, SAS, and Fibre Channel to get a dual-display view of both oscilloscope-generated decode annotations and protocol analyzer software views. Search on protocol data in a table and export table data to an Excel file.

Learn More

teledynelecroy.com/dl/3005

More Trigger Capability Isolates More Problems Quickly

12 GHz Edge trigger, 14.1 Gb/s truehardware serial trigger (optional, includes capability for 80-bit NRZ and 8b/10b symbol, ten different SMART triggers, four-stage Cascade™ triggering, Measurement trigger, and TriggerScan™ are all standard and allow you to isolate the problem quickly and begin to focus on the cause.



Get more insight with multiple views of your serial data transmissions.

Search and Scan to Understand

Search a captured waveform for hundreds of different measurement parameters or other conditions using WaveScan. Set complex conditions, view search results on the waveform and in a table, and quickly zoom and jump to an entry. "Scan" for events that can't be triggered in hardware.

DEEP INSIGHT CLARIFIES COMPLEX SIGNALS

All Oscilloscope Tools are Not Created Equal

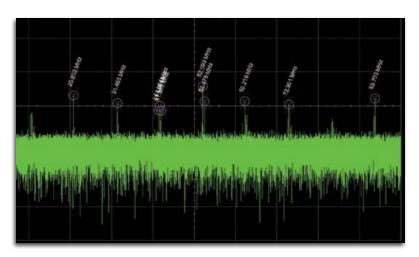
LabMaster 10 Zi-A has the deepest standard toolbox of any oscilloscope, providing more measure, math, graphing, statistical, and other tools, and more ways to leverage the tools to get the answer faster. While many other oscilloscopes provide similar looking tools, Teledyne LeCroy allows the most flexibility in applying the tools to any waveform.

Customized Tools

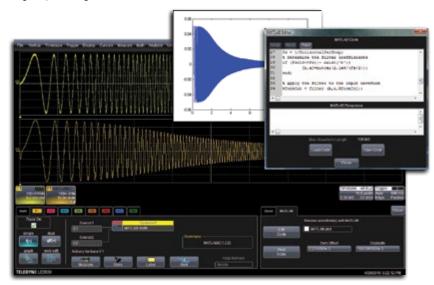
Only Teledyne LeCroy completely integrates third party programs into the oscilloscope's processing stream by allowing you to create and deploy a new measurement or math algorithm directly into the oscilloscope environment and display the result on the oscilloscope in real-time! There is no need to run a separate program, or ever leave the oscilloscope window. Use C/C++, MATLAB, Excel, JScript (JAVA), and Visual Basic to create your own customized math functions, measurement parameters, or other control algorithms.

Graphical Track, Trend, and Histogram Views

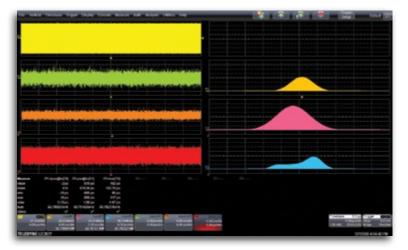
Track plots measurement values on the Y-axis and time on the X-axis to display a measurement change time-correlated to the original channel acquisition—perfect for intuitive understanding of behaviors in frequency modulated (FM) or pulse width modulated (PWM) circuits and jitter measurements, including modulation or spikes. Histograms provide a visual distribution representation of a large sample of measurements, allowing faster insight. Trends are ideal for plotting slow changes in measurement values.



X-Stream II fast throughput streaming architecture makes difficult analysis and deep insight possible. Above, an FFT is applied to a 50 Mpts waveform to determine root cause failure. The high frequency resolution this provides enables deep insight into signal pathologies.



XDEV Customization software package being used to implement a 1 MHz Butterworth filter using MATLAB®.



Capture a single clock channel (yellow) and display Track graphs and Histograms simultaneously of multiple jitter parameters.

MODULAR DESIGN FOR EXPANDABILITY

LabMaster 10 Zi-A leverages the unique LabMaster ChannelSync architecture with next-generation 8HP SiGe chipsets to produce the world's highest bandwidth, four channel oscilloscope – 36 GHz. When combined with patented DBI technology, bandwidth nearly doubles and triples, to 65 GHz and 100 GHz, with sample rates of 160 GS/s and 240 GS/s.

LabMaster 10 Zi-A oscilloscopes are fundamentally better – they are modular, inherently upgradeable, and infinitely flexible while retaining all the simplicity of operation expected from a conventional oscilloscope. LabMaster 10 Zi-A oscilloscopes can be configured for massive numbers of channels at up to 100 GHz – completely eliminating technology and test barriers.

ChannelSync technology ensures precise synchronization of all channels in all acquisition modules by using a single-distributed 10 GHz clock and a single trigger circuit. External clocking is not required, and trigger jitter from multiple trigger circuits is non-existent. Jitter between all channels is an ultra-low <130 fs_{rms}. Conventional 10 or 100MHz reference clocks simply cannot achieve this level of performance. Multi-module synchronization performance is identical to that provided with a single, standard oscilloscope package, and all captured waveforms and analysis appears on one oscilloscope display.

Typical LabMaster 10 Zi-A Systems

The Master Control Module (which includes the display) simply and quickly connects to one or more acquisition modules to create a functional, single oscilloscope package, but without the normal input channel or bandwidth limitations—operation is the same as a conventional oscilloscope. All waveforms are viewable on the built-in 15.3" display or on a variety of optional or user-supplied displays (up to 2560 x 1600 resolution). The entire system design speaks to a level of sophistication and integration not seen before in laboratory equipment.



4 Channels at 36 GHz

The base configuration is a LabMaster MCM-Zi-A Master Control Module and a single Acquisition Module. This provides four channels at up to 36 GHz and 80 GS/s. Acquisition modules are available at 20, 25, 30 and 36 GHz.



4 Channels at 65 GHz 8 Channels at 36 GHz

Build a 4-channel 65 GHz oscilloscope by connecting two acquisition modules. This system can also be used as an 8-channel, 36 GHz oscilloscope. In addition to 65 GHz acquisition modules, 50 and 59 GHz units are available.



The OC910 oscilloscope cart is ideal for housing systems with up to 4 acquisition modules.

Maximum Flexibility

Start with one Master Control Module and one Acquisition Module. Upgrade Acquisition Modules to include more memory or more bandwidth. Add additional acquisition modules at any time without returning equipment to the factory for modification or re-calibration.

Master Control Module

The LabMaster MCM-Zi-A Master Control Module provides the display, control panel, CPU, and ChannelSync 10 GHz distributed clock to provides precise and unmatched synchronization between all oscilloscope channels. High-speed PCIe cables connect to the acquisition modules for control and data transfer. The MCM-Zi-A includes a server-class CPU with Xeon™ E5-2680 v2 processors and 32 GB of RAM standard (up to 192 GB optional). Coupled with Teledyne LeCroy's X-Stream II architecture, the CPU muscles its way through the immense amounts of acquisition data made possible by LabMaster 10 Zi-A.

Additional Acquisition Modules

LabMaster 10 Zi-A acquisition modules are available at a variety of bandwidths, from 20 GHz to 100 GHz. All modules include four channels at 36 GHz bandwidth. The 50, 59, and 65 GHz models also provide 2 channels at the rated bandwidth; the 100 GHz module includes 1 channel. Each acquisition module is tightly integrated to the Master Control Module (MCM-Zi-A) with a ChannelSync 10 GHz distributed clock and two PCIe cables. Up to 20 acquisition modules can be used in one system. All acquired data is sent to the server-class CPU for processing.

ChannelSync Mainframe Hub

Easily expand beyond 5 acquisition modules with the LabMaster CMH-20Zi ChannelSync Mainframe Hub. The CMH-20Zi synchronizes up to 80 channels at 36 GHz with the same <130 fs precise performance as 4-channel system. The hub redistributes the 10 GHz clock and PCIe synchronization signals to up to 20 acquisition modules. One "card" is used for each connected acquisition module; cards can be purchased at any time to minimize the upfront cost.



OPTICAL-TO-ELECTRICAL CONVERTER (0E695G)



Teledyne LeCroy's OE695G wide-band optical-to-electrical converter is ideal for measuring optical datacom and telecom signals with data rates from 622 Mb/s to 12.5+ Gb/s. Connection to a real-time Teledyne LeCroy oscilloscope is through the 2.92 mm interface, with a provided adapter to connect to ProLink interfaces.

Built-in Reference Receiver

The OF695G contains built-in software reference receiver filters for common Fiber Channel, Ethernet, and ITU telecom standards. These reference receiver filters provide a 4-pole Bessel Thompson low pass filter response for the combined oscilloscope and optical-to-electrical (O-E) system with the -3dBe (electrical) at 0.75*bit rate. Combined passband response (compared to ideal) is ±1.6dBe (typical). If desired, a custom reference receiver for any bit rate up to 12.5Gb/s can also be applied. Additionally, the OE695G can be operated without any reference receiver applied, providing 9.5 GHz of bandwidth at -3 dB and Tr(10-90%) of approximately 45 ps when used with a Teledyne LeCroy oscilloscope of \geq 20 GHz of bandwidth.

Calibration Option for Maximum Accuracy

If guaranteed reference receiver response is required (±0.85 dB max through the passband, with a relaxed requirement through 1.5*bit rate, per the reference receiver requirement), the optional OE695G-REFCAL may be ordered with the OE695G. This will provide a documented calibration response for the various standard reference receivers and up to 12.5Gb/s "custom" reference receiver on all four oscilloscope channels at specific gain ranges (with typical response provided at other gain ranges).

Key Features

- Compatible with LabMaster 10 Zi oscilloscopes
- Frequency range DC to 9.5 GHz (electrical, -3 dB)
- Reference receiver support from 8GFC to 10GFC FEC, or Custom (<12.5Gb/s)
- Full bandwidth mode (no reference receiver applied)
- 62.5/125 μm multi-mode or single-mode fiber input
- Broad wavelength range (750 to 1650 nm)
- +7 dBm (5 mW) max peak optical power
- Low noise (as low as 25 pW/√Hz)
- Ideal for Eye Mask, Extinction Ratio, and Optical Modulation Amplitude (OMA) testing

HIGH BANDWIDTH PROBING SOLUTIONS

Ultra-wideband Architecture for Superior Signal Fidelity

Teledyne LeCroy's WaveLink® high bandwidth differential probes utilize advanced differential traveling wave (distributed) amplifier architecture to achieve superior high frequency analog broadband performance.

Highest Bandwidth (25 GHz) Solder-In Lead

Up to 25 GHz Solder-In performance with system (probe + oscilloscope) rise times equal to that of the oscilloscope alone.

Ultra-compact Positioner (Browser) Tip

The most compact positioner tip browser with bandwidth up to 22 GHz makes probing in confined areas easy.

Superior Probe Impedance Minimizes Circuit Loading

Circuit and signal loading is reduced by more than 50% with WaveLink high bandwidth probes compared to competitive probes. In the mid-band frequency range, the difference is even more apparent.

Superior Signal Fidelity and Lowest Noise

WaveLink has exceptional noise performance. In fact, the combination of the probe and the oscilloscope results in measurement performance that is nearly identical to that of a cable input.



D2505-A-PS 25 GHz probe system with Solder-In lead and browser positioner tip.

	D1305-A, D1305-A-PS	D1605-A, D1605-A-PS	D2005-A, D2005-A-PS	D2505-A, D2505-A-PS		
Bandwidth	Dxx05-SI and Dxx05-PT Tips 13 GHz	Dxx05-SI and Dxx05-PT Tips 16 GHz	Dxx05-SI and Dxx05-PT Tips 20 GHz	Dxx05-SI Lead 25 GHz Dxx05-PT Tip 22 GHz typical 20 GHz guaranteed		
Rise Time (10-90%)	Dxx05-SI and Dxx05-PT Tips 32.5 ps (typical)	Dxx05-SI and Dxx05-PT Tips 28 ps (typical)	Dxx05-SI and Dxx05-PT Tips 20 ps (typical)	Dxx05-SI Lead 17.5 ps (typical) Dxx05-PT Tip 19 ps (typical)		
Rise Time (20-80%)	Dxx05-SI and Dxx05-PT Tips 24.5 ps (typical)	Dxx05-SI and Dxx05-PT Tips 21 ps (typical)	Dxx05-SI and Dxx05-PT Tips 15 ps (typical)	Dxx05-SI Lead 13 ps (typical) Dxx05-PT Tip 14 ps (typical)		
Noise (Probe)	< 14 nV/√Hz (1.6 mV _{rms}) (typical)	< 14 nV/√Hz (1.8 mV _{rms}) (typical)	< 18 nV/√Hz (2.5 mV _{rms}) (typical)	< 18 nV/√Hz (2.8 mV _{rms}) (typical)		
Input Dynamic Range	2.0 V _{pk-pk} (±1.0 V) (nominal)					
Input Common Mode Voltage Range	±4 V (nominal)					
Input Offset Voltage Range	±2.5 V Differential (nominal)					
Impedance (mid-band, typical)	Dxx05-SI Lead: 300 Ω at 6 GHz, 525 Ω at 13 GHz, 600 Ω at 16 GHz, 300 Ω at 20 GHz, 120 Ω at 25 GHz					

600 Ω at 16 GHz, 300 Ω at 20 GHz, 120 Ω at 25 GHz **Dxx05-PT Tip:** 160 Ω at 6 GHz, 450 Ω at 13 GHz, 240 Ω at 16 GHz, 210 Ω at 20 GHz

SPARQ SIGNAL INTEGRITY NETWORK ANALYZER



network analyzers connect directly to the device under test (DUT) and to PC-based software through a single USB connection for quick, multi-port S-parameter measurements.

SPARQ is the ideal instrument for characterizing multi-port devices common in signal integrity applications at a fraction of the cost of traditional methods. It is ideal for:

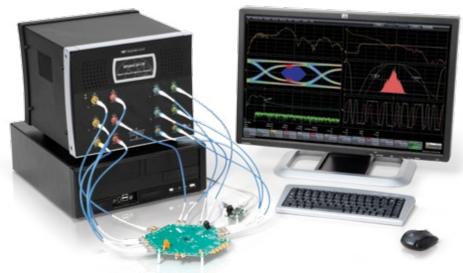
- Development of measurementbased simulation models
- Design validation
- Compliance testing
- High-performance TDR
- PCB testing
- Portable measurement requirements

High-bandwidth, Multi-port S-parameters for the Masses

S-parameter measurements are most often produced by the vector network analyzer (VNA), a difficult instrument that is beyond many budgets. SPARQ is very affordable and simplifies measurements, making S-parameters accessible to all.

PC-based, Small and Portable

Traditional instruments that produce S-parameters are large and fundamentally stationary. The SPARQ, in contrast, is small and weighs less than 20 lbs. It connects to any standard PC through a USB 2.0 interface, allowing SPARQ to run where computing power is easily upgraded.



S-parameters, Quick

VNA measurements begin with the unpleasant and complex task of calibration. This involves multiple connections that can produce misleading results due to operator error. The SPARQ provides calibrated measurements with a single connection to the DUT and offers simple setup choices. Start and complete the entire measurement with a single button press.

Internal Calibration

SPARQ takes a revolutionary approach to calibration by building in calibration standards. This enables measurements to be made without multiple connection steps and removes the need for additional electronic calibration (ECAL) modules. Calibration proceeds quickly without user intervention, so one can calibrate often without resorting to the use of out-of-date saved calibrations.

Characterize Crosstalk with 8 and 12-port SPARQs

Don't just model crosstalk – measure it. With the 8 and 12 port SPARQs, characterize interconnects with two and three differential lanes in order to obtain S-parameters needed for simulations of aggressor/victim/aggressor topologies.

Standard

Math Tools

Display up to 8 math function traces (F1-F8). The easy-to-use graphical interface simplifies setup of up to two operations on each function trace, and function traces can be chained together to perform math-on-math.

absolute value integral interpolate (cubic, quadratic, sinx/x) average (summed) average (continuous) invert (negate) correlation log (base e) (two waveforms) log (base 10) derivative product (x) deskew (resample) ratio (/) difference (-) reciprocal

enhanced resolution (to 11-bits vertical) rescale (with units)

envelope
exp (base e)
exp (base 10)
fft (power spectrum, magnitude, phase, up to max Mpts)
floor

roof
sparse
square
square
square root
sum (+)
zoom (identity)

Measure Tools

Display any 12 parameters together with statistics, including their average, high, low, and standard deviations. Histicons provide a fast, dynamic view of parameters and wave shape characteristics. Parameter Math allows addition, subtraction, multiplication, or division of two different parameters.

amplitude level @ x rms area maximum std. deviation base mean top cycles median width data minimum median narrow band phase delay phase Δ delay narrow band power time @ minimum (min.) duty cycle number of points time @ maximum (max.) duration + overshoot Δ time @ level falltime (90-10%, Δ time @ level overshoot 80-20%, @ level) from trigger peak-to-peak frequency x @ max period first x@min. risetime (10-90%, last 20-80%, @ level)

Pass/Fail Testing

Simultaneously test multiple parameters against selectable parameter limits or pre-defined masks. Pass or fail conditions can initiate actions including document to local or networked files, e-mail the image of the failure, save waveforms, send a pulse out at the front panel auxiliary BNC output, or (with the GPIB option) send a GPIB SRQ.

Basic Jitter and Timing Analysis Tools

This package provides toolsets for displaying parameter values vs. time, statistical views of parameters using histograms, and persistence view math functions. These tools include:

· "Track" graphs of all parameters, no limitation of number

- Cycle-Cycle Jitter - Period @ level - Setup - N-Cycle - Half Period - Hold - N-Cycle with - Width @ level - Skew start selection - Time Interval - Puty C

start selection — Time Interval — Duty Cycle @ level — Frequency @ level — Error @ level — Duty Cycle Error

- Histograms expanded with 19 histogram parameters and up to 2 billion events
- Trend (datalog) of up to 1 million events
- Track graphs of all parameters
- · Persistence histogram, persistence (range, sigma)

Standard (cont'd)

Advanced Customization

Provides capability to create a math function or measurement parameter in MATLAB, Excel, C++, JavaScript, or Visual Basic Script (VBS) format and insert it into the oscilloscope's processing stream. All results are processed and displayed on the oscilloscope grid, and are available for further processing. Also permits the creation of customized plug-ins that can be inserted into the scope user interface, control of the scope via Visual Basic scripts embedded in customized functions, and use of Teledyne LeCroy's Custom DSO capabilities.

Software Options

SDAIII Serial Data Analysis Software (LM10Zi-SDAIII) (Included in LM9Zi-SDAIII option, Standard on SDA MCM-Zi-A)

Total Jitter

A complete jitter measurement and analysis toolset with the SDAIII-CompleteLinQ user interface framework. The CompleteLinQ framework provides a single user interface for "LinQ", "Crosstalk", "EyeDrII" and "Virtual Probe" capabilities (purchased separately)

SDAIII provides complete serial data and clock jitter and eye diagram measurement and analysis capabilities. Eye Diagrams with millions of UI are quickly calculated from up to 512 Mpt records, and advanced tools may be used on the Eye Diagram to aid analysis. Complete TIE and Total Jitter (Tj) parameters and analysis functions are provided. Comparison of eye diagrams and jitter analysis between captured lanes and one "reference" location is provided. Includes:

- Time Interval Error (TIE) Measurement Parameter, Histogram, Spectrum and Jitter Track
- Total Jitter (Tj) Measurement Parameter, Histogram
- Spectrum
- · Eye Diagram Display (sliced)
- Eye Diagram IsoBER (lines of constant Bit Error Rate)
- Eye Diagram Mask Violation Locator
- Eye Diagram Measurement Parameters

Eye Height
 One Level
 Zero Level
 Eye Crossing
 Avg. Power
 Eye Amplitude
 Extinction Ratio
 Mask hits
 Mask out
 Bit Error Rate
 Slice Width (setting)

- · Q-Fit Tail Representation
- Bathtub Curve
- Cumulative Distribution Function (CDF)
- PLL Track

Jitter Decomposition Models

Three dual-dirac jitter decomposition methods are provided for maximum measurement flexibility. Q-Scale, CDF, Bathtub Curve, and all jitter decomposition measurement parameters can be displayed using any of the three methods.

- Spectral, Rj Direct
- Spectral, Rj+Dj CDF Fit
- NQ-Scale

Random Jitter (Rj) and Non-Data Dependent Jitter (Rj+BUj) Analysis

- Random Jitter (Rj) Meas Param
- Rj+BUj Spectrum
- Periodic Jitter (Pj) Meas Param
- Rj+BUj Track
- Rj+BUj Histogram
- Pi Inverse FFT

Deterministic Jitter (Dj) Analysis

• Deterministic Jitter (Dj) Measurement Parameter

Software Options (cont'd)

SDAIII Serial Data Analysis Software (continued)

Data Dependent Jitter (DDj) Analysis

- Data Dependent Jitter (DDj) Param
- Duty Cycle Distortion (DCD) Param
- InterSymbol Interference (ISI) Param
- · Digital Pattern display
- DDj Plot (by Pattern or N-bit Sequence)
- · DDj Histogram
- ISI Plot (by Pattern)

Reference Lane

 Compare current acquisition to Reference with a side-by-side or single (tabbed) display mode

SDAIII "LinQ" Capability

(SDAIII-Ling, SDAIII-CrossLing, and SDAIII-CompleteLing Options)

In addition to all SDAIII capabilities, "LinQ" options includes 4 lanes of simultaneous serial data analysis plus the reference lane. If EyeDrII or VirtualProbe are purchased with SDAIII "LinQ" capability, then those capabilities are provided for all four lanes.

Lanescape Comparison Mode

When multiple lanes are enabled for display, Lanescape Comparison Modes is used. Selections for this mode are as follows:

- · Single: One lane is displayed at a time.
- · Dual: Two lanes are selected for display.
- · Mosaic: All enabled lanes are displayed.

SDAIII "Crosstalk" Capability (Included in SDAIII-Crosstalk and SDAIII-CrossLinQ Options)

In addition to all SDAIII capabilities, "Crosstalk" options add the following noise and crosstalk measurements and analysis tools:

- Total, Random and Deterministic noise (Tn, Rn, Dn) measurements
- · Breakdown of Dn into InterSymbol Interference noise (ISIn) and Periodic noise (Pn)
- Noise-based eye height and width: EH(BER) and EW(BER)
- Random noise (Rn) + Bounded Uncorrelated noise (BUn) Noise Histogram
- · Q-fit for Noise Histogram
- Rn+BUn Noise Spectrum and Peak threshold
- Pn Inverse FFT Plot
- Rn+BUn Noise Track
- · Crosstalk Eye Contour Plot

SDAIII-CompleteLinQ

The ultimate in serial data single or multi-lane link analysis. Provides all the capabilities mentioned above in SDAIII, "LinQ", and "Crosstalk", and also includes EyeDrII and Virtual Probe capabilities.

Eye Doctor II Advanced Signal Integrity Tools (LM10Zi-EYEDRII)

Complete set of channel emulation, de-embedding and receiver equalization simulation tools. Provides capability to emulate a serial data link, de-embed or embed a fixture, cable or serial data channel, add or remove emphasis, and perform CTLE, FFE, or DFE equalization. If purchased with SDAIII, then capabilities are accessed from within the SDAIII-CompleteLinQ user interface framework.

Virtual Probe Signal Integrity Tools (LM10Zi-VIRTUALPROBE)

Provides ability to define a complex serial data channel or topology with up to six circuit elements that may be embedded or de-embedded, allowing "probing" at a location different than the measured position. If purchased with SDAIII and EyeDrll (or with the EYEDRII-VP or CompleteLinQ options), then capabilities are accessed from within the single SDAIII-CompleteLinQ user interface framework.

Software Options (cont'd)

Clock and Clock-Data Timing Jitter Analysis Package (LM10Zi-JITKIT)

Provides convenient setup and four views of jitter (statistical, time, spectrum, and overlaid) for a variety of horizontal, amplitude, and timing parameters. Direct display of jitter measurement values. Supports multiple simultaneous views with fast selection of multiple parameter measurements for fast and easy validation

Cable De-embedding (LM10Zi-CBL-DE-EMBED)

(Standard on SDA MCM-Zi-A)

Removes cable effects from your measurements. Simply enter the S-parameters or attenuation data of the cable(s) then all of the functionality of the SDA 8 Zi can be utilized with cable effects de-embedded.

8b/10b Decode (LM10Zi-8B10B D)

(Standard on SDA MCM-Zi-A)

Intuitive, color-coded serial decode with powerful search capability enables captured waveforms to be searched for user-defined sequences of symbols. Multi-lane analysis decodes up to four simultaneously captured lanes.

Spectrum Analyzer Mode (LM10Zi-SPECTRUM)

This package provides a new capability to navigate waveforms in the frequency domain using spectrum analyzer type controls. FFT capability added to include:

- · Power averaging
- Power density
- Real and imag components
- · Freq domain parameters
- FFT on up to 128 Mpts

Disk Drive Measurements Package (LM10Zi-DDM2)

This package provides disk drive parameter measurements and related mathematical functions for performing disk drive WaveShape Analysis. Disk Drive Parameters are as follows:

- amplitude asymmetry
- local base
- local baseline separation
- local maximum
- local minimum
- local number
- local peak-peak
- local time between events local time between peaks
- local time between troughs
- local time at minimum
- local time at maximum
- local time peak-trough
- local time over threshold

- local time trough-peak
- local time under threshold
- narrow band phase
- narrow band power
- overwrite
- pulse width 50
- pulse width 50 -
- pulse width 50 +
- resolution
- track average amplitude
- track average amplitude -
- track average amplitude +
- auto-correlation s/n
- non-linear transition shift

LabMaster 10 Zi Series	20 GHz	25 GHz	30 GHz	36 GHz	50 GHz	59 GHz	65 GHz	100 GHz	
Vertical System									
Analog Bandwidth $(0.50 \Omega (-3 dB))$ (1.85mm Inputs)					50 GHz (≥10 mV/div)	59 GHz (≥10 mV/div)	65 GHz (≥10 mV/div)	100 GHz (≥10 mV/div)	
Analog Bandwidth @ 50 Ω (-3 dB)	20 GHz (≥5 mV/div)	25 GHz (≥5 mV/div)	30 GHz (≥5 mV/div)			36 GHz (≥5 mV/div)			
(2.92mm Inputs) Rise Time (10–90%, 50 Ω) (test limit, flatness mode)	19.3 ps	15.4 ps	12.8 ps	10.7 ps	8.0 ps	6.9 ps	6.5 ps	4.5 ps	
Rise Time (20–80%, 50 Ω) (flatness mode)	14.5 ps	11.6 ps	9.6 ps	8.0 ps	6.0 ps	5.2 ps	4.9 ps	3.5 ps	
Input Channels			configuration s 80 2.92mm inpu		Up to 4		n configuration s @ 36 GHz.	elected.	
Bandwidth Limiters	1 GHz,	1 GHz,	1 GHz,	1 GHz,	For ≤ 36 GHz	For ≤ 36 GHz		GHz Mode:	
Banamath Emmes.	3 GHz,	3 GHz,	3 GHz,	3 GHz,	Mode:	Mode:		3 GHz,	
	4 GHz,	4 GHz,	4 GHz,	4 GHz,	1 GHz, 3 GHz,	1 GHz, 3 GHz,		6 GHz,	
	6 GHz,	6 GHz,	6 GHz,	6 GHz,	4 GHz, 6 GHz,			13 GHz,	
	8 GHz,	8 GHz,	8 GHz,	8 GHz,	8 GHz,	8 GHz,		. 20 GHz	
	13 GHz,	13 GHz,	13 GHz,	13 GHz,	13 GHz,	13 GHz,		GHz 33 GHz	
	16 GHz	16 GHz	16 GHz	16 GHz	16 GHz,	16 GHz,		Hz Mode:	
		20 GHz	20 GHz	20 GHz	20 GHz	20 GHz	50 GHz	, 60 GHz	
			25 GHz	25 GHz	25 GHz, 30 GHz, 33	25 GHz, 30 GHz,			
			20 02	30 GHz	GHz	33 GHz			
				33 GHz	For > 36 GHz	For > 36 GHz			
					Mode: None	Mode: 50 GHz			
Input Impedance		2.92mm Inpu	uts: 50 Ω ±2%				uts: 50 Ω ±2%		
					1.85mm Inputs: $50 \Omega \pm 2\%$				
					1mn	n Input: 50 Ω ±2	2% (10-100 Zi-A	only)	
Input Coupling		2.92 mm Inputs	s: 50 Ω: DC, GND)		2.92 mm Inputs	s: 50 Ω : DC, GNE)	
				1.85 mm Inputs: 50 Ω: DC					
					1mi		C (10-100 Zi-A d	only)	
Maximum Input Voltage	.0.1/		n Inputs:) ((I'			n Inputs:		
	±2 Vma	ax @ < 76 mV/div	/, 5.5V _{rms} @ ≥76	mV/div			<76 mV/div,		
					5.5V _{rms} @ ≥76 mV/div 1.85 mm Inputs: ±2 Vmax @ ≤80 mV/div				
							~		
Channel-Channel Isolation		DC to 26 CHz:	60 dB (>1000:1)			<u>:: ±2 vmax (ω ≤8</u> 6 GHz : 60 dB (>	0 mV/div (10-10	NA	
Chamilei-Chamilei isolation			nm input chann			vo 2.92mm inpu		IVA	
			div settings, typ			ferent v/div sett			
	San	ic or different v/	div Settings, typ	icaij		55 GHz : 40 dB (
	(For any two 1.85mm input channels,								
					same or different v/div settings, typical)				
Vertical Resolution				o 11 bits with e	enhanced resolut				
Sensitivity			.92mm):				.92mm):		
			div, fully variable				div, fully variable		
		(5-9.9 mv/c	liv via zoom)				div via zoom)		
							mm, 1mm): div, fully variable		
							ossible through		
					riigrici		ttenuators.	436 01	
DC Vertical Gain Accuracy (Gain Component of		:	±1% F.S. (typical), offset at 0V; ±	±1.5% F.S. (test li				
DC Accuracy)									
Vertical Noise Floor	1.39 mV _{rms}	1.57 mV _{rms}	1.69 mV _{rms}	1.88 mV _{rms}	3.1 mV _{rms}	3.7 mV _{rms}	3.9 mV _{rms}	5.4 mV _{rms}	
(50 mV/div) Offset Range	(typical)	(typical)	(typical) Ω:	(typical)	(typical)	(typical)	(typical) . 92mm) :	(typical)	
onset hange			5-75 mV/div				.92mm): 5-75 mV/div		
		_	'div -500mV/div			_			
		±4 v @ /0111V/	aiv Journa/aiv		± 4 V @ 76 mV/div -500mV/div 50 Ω (1.85 mm, 1mm) :				
							10-80 mV/div		
DC Vertical Offset Accuracy			±(1.5% of o	ffset setting +	1.5% F.S. + 1 mV				

LabMaster 10 Zi Series	20 GHz	25 GHz	30 GHz	36 GHz	50 GHz	59 GHz	65 GHz	100 GHz	
Horizontal System									
Timebases			e with 10 GHz cl						
	10 (r all channels en lentical to that n					all	
ime/Division Range	10 ps/div-256 s	channels identical to that provided within a single, conventional oscilloscope package. 10 ps/div-256 s/div (maximum capture time is based on For >36 GHz Mode:							
·	minimum samp	le rate of 200)kS/s and install	led memory).		10 ps/div -			
					(maxim	um capture time		60 GS/s	
						and installe For ≤36 G			
					10 ps/div-25	56 s/div (maxim		ne is based or	
					minimum saı	mple rate of 200	kS/s and insta	alled memory)	
Clock Accuracy					om/yr from last				
Sample Clock Jitter					uired Time Rang mebase Referer				
					imebase Referei				
					uired Time Rang				
					imebase Refere				
			130f	s _{rms} (External T	<u>imebase Refere</u>	nce)			
Delta Time Measurement		$rac{1}{2}$	Noise \\^2 +						
Accuracy	•	$\sqrt{2} * \left \left(-\frac{1}{3} \right) \right $	+	(Sample Clock	k Jitter _{rms})² + (clock accuracy	* reading)		
Catan Management Elemen		$\frac{1}{\sqrt{1}}$	· · · · · · · · · · · · · · · · · · ·						
Jitter Measurement Floor		17	Noise \setminus^2	(0 1 0)					
] (-	$\frac{Noise}{SlewRate}$ +	(Sample Clock	(Jitter _{rms})²				
1'11 D 1 Ol 1		, ,				1500	10	0.0	
litter Between Channels Measured at maximum		<250	fs _{rms}		<190fs _{rms}	<150fs _{rms}	<13	Ofs _{rms}	
pandwidth)									
Frigger and Interpolator		<	0.1 ps _{rms} (typical	al, software ass	isted), 2 ps _{rms} (t	ypical, hardware	9)		
Jitter Channel-Channel Deskew			, time o /div o ottin	a or OE no mov	(which over in In	raar) aaab abar	un al		
Snannel-Channel Deskew Range		±9)	x time/div. settin	ig or 25 ns max.	. (whichever is ia	irger), each char	inei		
External Timebase		10 MHz; 50	Ω impedance, a	applied at the re	ear input of MCM	1-Zi Master Cont	rol Module		
Reference (Input)									
External Timebase Reference (Output)		10 MHz	; 50 Ω impedand	ce, output at the	rear of MCM-Zi	Master Control	Module		
hererice (Output)									
and the second second									
Acquisition System									
Acquisition System Single-Shot Sample Rate/Ch		80 GS/s on e	each channel.			/s on each chan			
		80 GS/s on e	each channel.		160 GS	S/s on each cha	nnel in >36 GH	z Mode.	
Single-Shot Sample Rate/Ch				rms/second (in	160 GS 240	S/s on each char GS/s on 100 GH	nnel in >36 GH z (10-100 Zi-A	z Mode.	
			each channel. 000,000 wavefo	,	160 GS 240	S/s on each char GS/s on 100 GH	nnel in >36 GH z (10-100 Zi-A	z Mode.	
Single-Shot Sample Rate/Ch Maximum Trigger Rate Intersegment Time Maximum Acquisition		1,1		,	160 GS 240 Sequence Mode µs	S/s on each char GS/s on 100 GH	nnel in >36 GH z (10-100 Zi-A ls)	z Mode. only) 1536 Mpts	
Single-Shot Sample Rate/Ch Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory		1,1	000,000 wavefo pts/Ch	1	160 GS 240 Sequence Mode µs 1024 Mp	S/s on each char GS/s on 100 GH e, up to 4 channe ots/Ch (2 Ch ope	nnel in >36 GH z (10-100 Zi-A ls)	z Mode. . only)	
Single-Shot Sample Rate/Ch Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory		1,1	000,000 wavefo pts/Ch	1 Option (See belo	160 GS 240 Sequence Mode µs 1024 Mp	S/s on each char GS/s on 100 GH e, up to 4 channe ots/Ch (2 Ch ope	nnel in >36 GH z (10-100 Zi-A ls)	z Mode. only) 1536 Mpts	
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments)		1,1	000,000 wavefo pts/Ch	1 Option (See belo	160 GS 240 Sequence Mode µs 1024 Mp	6/s on each char GS/s on 100 GH e, up to 4 channe ots/Ch (2 Ch ope memory length)	nnel in >36 GH z (10-100 Zi-A ls)	z Mode. only) 1536 Mpts	
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments)		1,i	000,000 wavefo pts/Ch S-32 Memory C	Dption (See belo	160 GS 240 Sequence Mode µs 1024 Mp w for details on 500)	6/s on each char GS/s on 100 GH e, up to 4 channe ots/Ch (2 Ch ope memory length)	nnel in >36 GH z (10-100 Zi-A s) ration	z Mode. only) 1536 Mpts	
Maximum Trigger Rate Intersegment Time Maximum Acquisition Memory Standard Memory (Number of Segments)	S-32 M-6	1,i 512 Mi	000,000 wavefo pts/Ch S-32 Memory C ≤ 36 GHz/Ch 32 Mpts	Dption (See belo (3,5 50-65 GHz 64 Mpts	160 GS 240 Sequence Mode µs 1024 Mp w for details on 500) 100 GHz 96 Mpts	6/s on each char GS/s on 100 GHz, up to 4 channe ots/Ch (2 Ch ope memory length) Number	nnel in >36 GH z (10-100 Zi-A lls) ration) Segments	z Mode. only) 1536 Mpts	
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Ary Ch 1-4 (Edge, Window, SMARI, Cassaele triggers), AUX, internal Fast Edge, or any input channel (Edge trigger only) on a discoal ToxaC Acquisition Modules (Channels 5 and higher) Slope and level unique to each source except line triager. Dot. AU, FFRey I FFley Pre-trigger Delay Do-1000 of visions in rest time mode, limited at slover time discussing. For Ch 1-8 of a tabMaster to 21 system. Edge fringer For Ch 1-8 of a tabMaster to 21 system. Edge fringer (LBS7 2 22mm Inputs) For Ch 1-4 of a tabMaster to 21 system. Edge fringer (LBS7 22mm Inputs) For Ch 1-4 of a tabMaster to 10-4 system. Edge Fringer For Ch 1-4 of a tabMaster to 10-4 system. Edge Fringer (LBS7 2 22mm Inputs) For Ch 1-4 of a tabMaster to 10-5 Acquisition Module. Edge Fringer (LBS7 2 22mm Inputs) For Ch 1-4 of a tabMaster to 10-5 Acquisition Module. Edge Fringer For Ch 1-4 of a tabMaster to 10-5 Acquisition Module. Edge Fringer For Ch 1-4 of a tabMaster to 10-5 Acquisition Module. Edge Fringer For Ch 1-4 of a tabMaster to 10-5 Acquisition Module. Edge Fringer Frequency, For Ch 1-4 of a tabMaster to 10-5 Acquisition Module and the system of the system o		Normal Auto Single and Ston							
Coupling Mode DC, AC, HFRej, LFRej Pretrigger Delay O-100% of memory size disputable in 1% increments of 100 ns) Post-trigger Delay O-10,000 divisions in real time mode, limited at slower time/divisettings Indicided fib. Time or Evente From 2 ns. up to 20 a crif from 1-10 stopp 309 evente Internal Trigger Renae Trigger Sensitivity with For Ch 1-80 of a Lab Moster 10 2 system: 1,8 div. @ 48 GHz (1,6 fe/2 92mm Inputs) Faternal Trigger Sensitivity (Edge Trigger) For Ch 1-4 only of any Lab Master 10 tox 71 Acquisition Module. (Edge Trigger) For Ch 1-4 only of any Lab Master 10 tox 71 Acquisition Module. (Edger Trigger Frequency. For Ch 1-4 only of any Lab Master 10 tox 71 Acquisition Module. (Edger Trigger Frequency. For Ch 1-4 of a Lab Master 10 xx-2 to Acquisition Module. (Edger Trigger Input. Max. Trigger Frequency. SAAPIT Intigger 2, 0 GHz @ 1 Ch 1/2 Charter 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition Module. (Edger Intigger Input. For any Lab Master 10 xx-2 to Acquisition M		Any Ch 1-4 (Edge, Window, SMART, Cascade triggers), AUX, internal Fast Edge; or any input channel (Edge trigger only) on ad							
Prictinger Delay O=10003 of memory size (adjustable in 1% increments of 100 ns) Post-trigger Delay O=10003 of invisions in real time mode, limited at Sewer time/div settings Hold off by Time or Events From 2 ns up to 20 s or from 1 to 99,999,999 events Internal Trigger Bange 1.85 of 2 1.20 by 5 1.20 by 6 1.20 by 6 1.20 by 5 1.20 by 6 1.2	- "								
Post-trigger Delay				0 1000; f			. (100	`	
Hold off by Time or Events Honder Plange Hold of the John centre History Flager Sensitivity with Eager Register (1.85/2.92mm Inputs) Description (1.85/2.92mm Inputs) Descript									
Internal Trigger Sange Trigger Sensitivity with For Ch 1-90 of a LabMaster 10 Zi system: 2 de 2 de 2 de 2 1.6 de 2 de 3 de 3 de 3 de 3 de 3 1.6 de 2 de 3			0-1					tings	
Trigger Sensitivity with For Ch 1 80 of a LabMaster 10 Zi system: Edge Trigger (1.85/2.97mm Inputs) 1.5 diw @ + 80 CHz 1.0 diw @ + 50 CHz 1.0 diw				From 2 ns			199 events		
Edge Triggers (1.85/2.92mm Inputs) External Trigger Sensitivity, (For DC coupling, at 10 mW/dis, 50 Q) External Trigger Sensitivity, (For DC coupling, at 10 mW/dis, 50 Q) External Trigger Sensitivity, (For Ch 1.4 only of any 1 abMassier 10xx 2 Acquisition Module: 2. div. @ < 1.0 cit. Qi. Ch2. 3. 1.5 div. @ < 500 MHz. 4. 1.0 div. Qi. Ch2. 4. 2.0 SHz. @ 3.10 mW/div. Minimum triggers be width 200 ps) External Trigger Input 4. For any 1 abMassier 10xx 2 it acquisition Module in Section Module. SMART Inger (Ingly Ch. 1-4 Acquisition Module has catter. AUX input) Basic Triggers Glony Ch. 1-4 Acquisition Module has catter. AUX input) Basic Triggers Glony Ch. 1-4 Acquisition Module has catter. AUX input) Basic Triggers State or Fdge Qualified Triggers when signal meets slope (positive, negative, or either) and level condition. Triggers when signal exits a window defined by adjustable thresholds SMART Triggers State or Fdge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events Triggers on companies of the acquisition, Inclided between sources is selectable by time or events Dropput Triggers in Charles of the acquisition, Inclided between sources is selectable by time or events Triggers on positive or negative up the selectable sources in selectable by time or events Dropput Triggers in the Input Aux of the acquisition, Inclided between sources is selectable by time or events Triggers on positive or negative up that with widths selectable as low as 2000 sto 20 s, or on intermittent faults Triggers on positive or negative up that with widths selectable as low as 2000 sto 20 s, or on intermittent faults Triggers on any source of a given state (or transition edge) has occurred on another source Triggers on expositive or nega				For			rtem:		
(1.85/2.92mm Inputs) 1.5 div @ = 6 GHz (for DC coupiling, ≥ 1) or w/div, 50 Q) External Trigger Sensitivity, For Ch 1-4 only of any Labbastant Tlox-2A Equisition Module: 2 div @ > 1 GHz, 2 div @ > 500 MHz, 1.0 div @ \$00 MHz, 1.0 div				101			occiii.		
External Trigger Sensitivity, (Edge Trigger) External Trigger Prout For Ch 1-4 of a LabMisater 10xx-21 Acquisition Module Sensitive Aux (20.4 V) Range (Only Ch 1-4 Acquisition Module Aux (20.4 V) Range (Only Ch 1-4 Acquisition Module Aux (20.4 V) Range (Only Ch 1-4 Acquisition Module Aux (20.4 V) Range (Only Ch 1-4 Acquisition Module Aux (20.4 V) Range Triggers When signal meets slope (positive, negative, or either) and level condition. Triggers when signal exits a window defined by adjustable thresholds SMART Triggers* State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events Trigger in Edge Trigger Sensition Holdoff between sources is selectable by time or events Trigger in Edge Trigger Sensition Holdoff Sensition									
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Exemal Trigger Sensitivity, (Edge Trigger) Row (2 hough stort (10 kg) 2 hough stort (1				(+		•	<i>3</i>)		
(Edge Trigger) 1 2 diw @ < 10 MHz, 1.0 diw @ < 200	External Trigger Sensitivity								
1.5 dw				1010111 4011			iisition wodalc.		
1.0 dw ⊗ < 200 MHz, (for DC coupling)	(Lage Migger)								
Max. Trigger Frequency, SIMART Trigger 2.0 GHz ⊗ ≥ 10 mV/div (minimum triggerable width 200 ps) External Trigger Input For any LabMaster 10xx 21 Acquisition Module: Aux (4.4 4 V) Range (0h) Ch 1 4 Acquisition Module has "active" AUX Input) Basic Triggers Basic Triggers Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal exits a window defined by adjustable thresholds SMART Triggers* State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events In Sequence acquisition mode, triggers repeatably on event B only if a defined pattern, state, or edge (event A) is satisfied in the first segment of the acquisition. Holdoff between sources is and 20 s Pattern Logic combination (AND, NAND, OR, NOR) of 5 inputs (4 channels and external trigger input). Each source can be high, low, of don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern SMART Triggers with Exclusion Technology Glitch Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults Trigger on positive or negative nutrs defined by two voltage limits and two time limits. Select between 1 ns and 20 ns Trigger on edger rates. Select limits for dV, dt, and slope. Selectage limits and two time limits. Select between 1 ns and 20 ns Trigger on edger rates. Select limits for dV, dt, and slope. Sel									
Max. Trigger Frequency, SAMART Trigger 2.0 GHz @a. 2 In DriVdiv (minimum triggerable) External Prigger Input Rapper Basic Triggers Basic Triggers Basic Triggers Basic Triggers Basic Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal exits a window defined by adjustable thresholds SMART Triggers State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events Qualified First In Sequence acquisition mode, triggers repeatably on event B only if a defined pattern, state, or edge (event A) is satisfied in the first segment of the acquisition. Holdoff between sources is selectable by time or events Dropout Triggers if signal drops out for longer than selected lime between 1 ns and 20 s Pattern Logic combination (AND, NAND, OR, NNR) of 5 inputs (4 channels and external trigger input). Each source can be high, low, of don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern SMART Triggers with Exclusion Technology Glitch Triggers on positive or negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults Width (Signal or Pattern) Triggers on any source if a given state (or transition edge) has occurred on another source. Trigger on positive or negative runs defined by two voltage limits and two time limits. Select between 1 ns and 20 s Trigger on regative or negative runs defined by two voltage limits and two time limits. Select between 1 ns and 20 ns Trigger on intermittent faults by specifying the expected behavior and trigger on "C" event. Or Arm on "A" event, then Qualify on "B" event, and Trigger on "C" event. Or Arm on "A" event, then Qualify on "B" event, and Trigger on "C" event. Or Arm on "C" event, and Trigger on "C" event. Or Arm on "C" event, then Cuglify o									
External Trigger Input Range (Only Ch 1-4 Acquisition Module: Aux (±0.4 V) Range (Only Ch 1-4 Acquisition Module has "active" AUX Input) Basic Triggers Edge Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal meets slope (positive, negative, or either) and level condition. SMART Triggers" State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events In Sequence acquisition mode, triggers repeatably on event B only if a defined pattern, state, or edge (event A) is satisfied in the first segment of the acquisition. Holdoff between sources is selectable by time or events Dropout Triggers if signal drops out for longer than selected time there in 1s and 20 s Pattern Logic combination (AND, NAND, OR, NOR) of 5 inputs (4 channels and external trigger input). Each source can be high, low, or don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern SMART Triggers with Exclusion Technology Glitch Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on any source if a given state (or transition edge) has occurred on another source. Trigger on positive or negative units defined by two voltage limits and two time limits. Select between 1 ns and 20 ns Exclusion Triggering Trigger on edge rates. Select limits for dV, dt, and slope. Select degle limits between 1 ns and 20 ns Trigger on edge rates. Select limits for dV, dt, and slope. Select degle limits between 1 ns and 20 ns Trigger on edge rates. Select limits for dV, dt, and slope. Select degle limits between 1 ns and 20 ns Trigger on edge rates. Select limits for dV, dt, and slope. Select degle limits between 1 ns and 20 ns Trigger on edge rat	Max. Trigger Frequency,			For Ch 1-4			on Module:		
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Edge Triggers when signal meets slope (positive, negative, or either) and level condition. Window Triggers when signal exits a window defined by adjustable thresholds SMART Triggers* State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events In Sequence acquisition mode, triggers repeatably on event B only if a defined pattern, state, or edge (event A) is satisfied in the first segment of the acquisition. Holdoff between sources is selectable by time or events Dropout Triggers if signal drops out for longer than selected time between 1 ns and 20 s Pattern Logic combination (AND, NAN, OR, NO, PA) of 5 inputs (4 channels and external trigger input). Each source can be high, low, or don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern SMART Triggers with Exclusion Technology Glitch Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Interval (Signal or Pattern) Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults Interval (Signal or Pattern) Triggers on positive or negative provides a given state (or transition edge) has occurred on another source. Trigger on aps source if a given state (or transition edge) has occurred on another source. Trigger on positive or negative runts defined by two voltage limits and two time limits. Select between 1 ns and 20 ns Exclusion Triggering Trigger on a positive or negative runts defined by two voltage limits and two time limits. Select between 1 ns and 20 ns Trigger on intermittent faults by specifying the expected behavior and trigger on "C" event. Types Cascade (Sequence) Triggering Cascade (Sequence) Triggering Cascade (Sequence) Triggering Cascade (Sequence) Triggering Cascade A then B then C (Measurement). Edge, Window, Pattern (Logic), Width, Glitch, Interva	Range			(Only Ch 1-	4 Acquisition Mo	dule has "active	" AUX Input)		
SMART Triggers™ State or Edge Qualified Triggers on any input source only if a defined state or edge occurred on another input source. Holdoff between sources is selectable by time or events Qualified First In Sequence acquisition mode, triggers repeatably on event B only if a defined pattern, state, or edge (event A) is satisfied in the first segment of the acquisition. Holdoff between sources is selectable by time or events Dropout Triggers if signal drops out for longer than selectated time between 1 ns and 20 s Pattern Logic combination (AND, NAND, OR, NOR) of 5 inputs (4 channels and external trigger input). Each source can be high, low, or don't care. The High and Low level can be selected independently. Triggers at start or end of the pattern SMART Triggers with Exclusion Technology Glitch Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Width (Signal or Pattern) Triggers on positive, negative, or both widths with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive or negative glitches with widths selectable as low as 200ps to 20 s, or on intermittent faults Triggers on positive or negative glitches with widths selectable between 1 ns and 20 s Trigger on positive or negative glitches with widths selectable between 1 ns and 20 s Trigger on positive or negative glitches with widths selectable between 1 ns and 20 s Trigger on positive or negative glitches with widths selectable by time time time the selectable selectable sele	Basic Triggers								
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LabMaster 10 Zi Series	20 GHz	25 GHz	30 GHz	36 GHz	50 GHz	59 GHz	65 GHz	100 GHz
High-speed Serial Proto								
Data Rates	Option LM10Zi-6GBIT-80B-8B10B-TD: 600 Mb/s to 6.5 Gb/s, Channel 4 input only Option LM10Zi-14GBIT-80B-8B10B-TD: 600 Mb/s to 14.1 Gb/s, Channel 4 input only 600 Mb/s to 14.1 Gb/s, Channel 4 input only 600 Mb/s to 14.1 Gb/s, Channel 4 input only (Note: Channel 3 input will capture signal for the company of						ut only 3-TD: out only gnal for	
							cope is in ≥25 G	Hz mode)
Pattern Length				D-bits, NRZ or eig				
Clock and Data Outputs			No Clo	ock and Data Red	covery outputs p	orovided		
Color Waveform Display	1							
Type		Oı		CM-Zi-A Master C Matrix LCD with			anel	
Resolution			TITACTIVE) x 768 pixels	Oddii Sciccii		
Number of Traces	С	isplav a maxim	um of 40 traces	s. Simultaneously		l. zoom. memor	v and math trac	es
Grid Styles				Octal, X-Y, Single				
Waveform Representation		7.0.0, 0.1	Sai	mple dots joined,	or sample dots	only	on, money	
Integrated Second Displ	lay							
Туре	Supp			fuser-supplied se			ability.	
5 1.2		(Note: toucl		or second displa		-ujitsu driver)		
Resolution			Determine	ed by display cho	sen by user			
High-Speed Digitizer Ou	utput (Option)							
Type				lls in LabMaster				
T (D :				t normally used b				
Transfer Rates Output Protocol				ximum of 4 char 1 (4 lanes utilize			or >4 channels)	
Control Protocol		P	Ci Express, Gen	TCP/IP	u ioi uata transi	ier)		
Command Set		Via Window	vs Automation, o	or via Teledyne Le	Croy Remote C	ommand Set		
Processor/CPU								
Type				lule: Intel® Xeon				
	CPU,	<u>and each proce</u>		es for a total of 2			sor speed of 33	.6 GHz.
Processor Memory				tandard. Up to 19				
Operating System			Microso	ft Windows® 7 Pr	ofessional Edition	on (64-bit)		
Real Time Clock	Date and time displayed with waveform in hardcopy files. SNTP support to synchronize to precision internal clocks						nal clocks	
Setup Storage								
Front Panel and Instrument Status		Store to the	e internal hard d	rive, over a netw	ork, or to a USB-	connected perip	oheral device	
Interface								
Remote Control		Via	Windows Autor	nation, or via Tele	edyne LeCroy Re	emote Comman	d Set	
Network Communication Standard			VXI-1	1 or VICP, LXI Cl	ass C (v1.2) Con	npliant		
GPIB Port (optional)				lls in LabMaster I mally used by a L				
LSIB Port (optional)	Supports PCI	e Gen1 x4 proto	ocol with Teledyr	ne LeCroy supplied lot normally used	ed API. Installs ir	n LabMaster MC	CM-Zi-A Master (
Ethernet Port		a abco one		100/1000BaseT				
USB Ports				aster MCM-Zi-A				
		minimum		ports on rear of u			tible devices	
				laster MCM-Zi-A				
		minimum 3		orts on front of a			tible devices	
External Monitor Port	Dual Link DVI			display on MCM				esolution) and
				WQXGA (2560				

Warranty and Service

25 GHz LabMaster 10 Zi Series **20 GHz 30 GHz** 36 GHz 50 GHz 59 GHz 65 GHz 100 GHz **Power Requirements** LabMaster 10-xxZi-A Acquisition Module: Voltage 100-240 VAC ±10% at 45-66 Hz; 100-120 VAC ±10% at 380-420 Hz; Automatic AC Voltage Selection, Installation Category II LabMaster MCM-Zi-A Master Control Module: 100-240 VAC ±10% at 45-66 Hz: Automatic AC Voltage Selection, Installation Category II LabMaster 10-xxZi-A Acquisition Module - 1225 W / 1225 VA. LabMaster 10-xxZi-A Acquisition Module -Max. Power Consumption 1275 W / 1275 VA. LabMaster MCM-Zi-A Master Control Module - 450 W / 450 VA. Each Module and the CPU has a separate power cord. LabMaster MCM-Zi-A Master Control Module -450 W / 450 VA. Each Module and the CPU has a separate power cord. **Environmental** +5 °C to +40 ° Temperature (Operating) Temperature -20 °C to +60 °C (Non-Operating) Humidity (Operating) 5% to 80% relative humidity (non-condensing) up to +31 °C Upper limit derates to 50% relative humidity (non-condensing) at +40 °C Humidity (Non-Operating) 5% to 95% relative humidity (non-condensing) as tested per MIL-PRF-28800F Altitude (Operating) Up to 10,000 ft. (3048 m) at or below +25 °C Altitude (Non-Operating) Up to 40,000 ft. (12,192 m) Random Vibration 0.5 g_{rms} 5 Hz to 500 Hz, 15 minutes in each of three orthogonal axes (Operating) Random Vibration 2.4 grms 5 Hz to 500 Hz, 15 minutes in each of three orthogonal axes (Non-Operating) **Functional Shock** 20 gpeak, half sine, 11 ms pulse, 3 shocks (positive and negative) in each of three orthogonal axes, 18 shocks total **Physical Dimensions** Dimensions (HWD) LabMaster MCM-Zi-A Master Control Module - 10.9"H x 18.2"W x 15.6"D (277 x 462 x 396 mm), LabMaster 10-xxZi-A Acquisition Module - 8.0"H x 18.2"W x 26"D (202 x 462 x 660 mm) Weight LabMaster 10-xxZi-A Acquisition Module -LabMaster 10-xxZi-A Acquisition Module -53 lbs. (24 kg) 58 lbs. (24 kg) LabMaster MCM-Zi-A Master Control Module -LabMaster MCM-Zi-A Master Control Module -47 lbs. (21.4 kg) 47 lbs. (21.4 kg) Shipping Weight LabMaster 10-xxZi-A Acquisition Module -LabMaster 10-xxZi-A Acquisition Module -71 lbs. (32.3 kg) 76 lbs. (34.5 kg) LabMaster MCM-Zi-A Master Control Module -LabMaster MCM-Zi-A Master Control Module -56 lbs. (25.5 kg) 56 lbs. (25.5 kg) **Certifications** CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12

3-year warranty; calibration recommended annually.

Optional service programs include extended warranty, upgrades, and calibration services

ORDERING INFORMATION

Product Description

Product Code

Product Description

Product Code

LabMaster 10 Zi-A Series Master Control Modules

LabMaster Master Control Module with 15.3"	LabMaster MCM-Zi-A
WXGA Color Display.	
SDA Master Control Module with 15.3" WXGA Color	SDA MCM-Zi-A
Display (provides add'l standard software and	
64 Mpt/Ch memory)	

LabMaster 10 Zi-A Series Acquisition Modules

Eubividater To Zi A deries Acquisition i	vioudics
20 GHz, 80 GS/s, 4 Ch, 32 Mpts/Ch	LabMaster 10-20Zi-A
LabMaster 10 Zi Acquisition Module	
with 50 Ω input	
25 GHz, 80 GS/s, 4 Ch, 32 Mpts/Ch	LabMaster 10-25Zi-A
LabMaster 10 Zi Acquisition Module	
with 50 Ω input	
30 GHz, 80 GS/s, 4 Ch, 32 Mpts/Ch	LabMaster 10-30Zi-A
LabMaster 10 Zi Acquisition Module	
with 50 Ω input	
36 GHz, 80 GS/s, 4 Ch, 32 Mpts/Ch	LabMaster 10-36Zi-A
LabMaster 10 Zi Acquisition Module	
with 50 Ω input	
50 GHz, 160 GS/s, 2 Ch, 64 Mpts/Ch	LabMaster 10-50Zi-A
LabMaster 10 Zi Acquisition Module	
with 50 Ω input	
(36 GHz, 80 GS/s, 4 Ch, 32 Mpts/Ch)	
59 GHz, 160 GS/s, 2 Ch, 64 Mpts/Ch	LabMaster 10-59Zi-A
LabMaster 10 Zi Acquisition Module	
with 50 Ω input	
(36 GHz, 80 GS/s, 4 Ch, 32 Mpts/Ch)	
65 GHz, 160 GS/s, 2 Ch, 64 Mpts/Ch	LabMaster 10-65Zi-A
LabMaster 10 Zi Acquisition Module	
with 50 Ω input	
(36 GHz, 80 GS/s, 4 Ch, 32 Mpts/Ch)	
100 GHz, 240 GS/s, 2 Ch, 96 Mpts/Ch	LabMaster 10-100Zi-A
LabMaster 10 Zi Acquisition Module	
with 50 Ω input	
(36 GHz, 80 GS/s, 4 Ch, 32 Mpts/Ch)	

Included with LabMaster MCM-Zi-A Standard Configuration

Power Cable for the Destination Country, Optical 3-button Wheel Mouse USB 2.0, Printed Getting Started Manual, Anti-virus Software (Trial Version), Microsoft Windows 7 License, Commercial NIST Traceable Calibration with Certificate, 3-year Warranty

Included with LabMaster 10-xxZi-A Standard Configuration

2.92mm Connector Saver: Qty. 4, 1.85mm Barrel Adapter: Qty. 2 (50-65 GHz units only), PCIe x 8 cable, 2m long, PCIe x 4 cable, 2m long, Power Cable for the Destination Country, ChannelSync 10 GHz clock cable, 2m long, Commercial NIST Traceable Calibration with Certificate, 3-year Warranty

ChannelSync Expansion Products

ChannelSync Mainframe Hub to permit	LabMaster CMH20-Zi
LabMaster expansion to up to	
20 acquisition modules	
Expansion ChannelSync module card for	LabMaster CMH-1ACQMODULE-Zi
ChannelSync Mainframe Hub.	
One required per connected	
acquisition module	

Memory Options

LM10Zi-STD
SDA10Zi-STD
LM10Zi-M-64
LM10Zi-L-128
SDA10Zi-L-128
LM10Zi-L-256
SDA10Zi-L-256
LM10Zi-XL-512
SDA10Zi-XL-512

CPU, Computer and Other Hardware Options
for LahMaster MCM-7i-A Master Control Module

Additional 500 GB Hard Drive for MCM-Zi-A	MCMZi-500GB-RHD-02
Upgrade to 64 GB RAM for MCM-Zi-A	MCMZI-32-UPG-64GB
Upgrade to 128 GB RAM for MCM-Zi-A	MCMZI-32-UPG-128GB
Upgrade to 192 GB RAM for MCM-Zi-A	MCMZI-32-UPG-192GB
GPIB Option for LabMaster MCM-Zi-A	GPIB-3

Serial Data and Crosstalk Analysis

Product Description

Bundle - Multi-Lane SDA LinQ	LM10Zi-SDAIII-CompleteLinQ
Framework, including Eye, Jitter, Noise,	SDA10Zi-CompleteLinQ
Crosstalk Measurements, with EyeDrII	DDA10Zi-CompleteLinQ
and VirtualProbe	<u> </u>
Multi-Lane Serial Data Analysis LinQ	LM10Zi-SDAIII-CrossLinQ
Framework, Eye, Jitter, Noise and	SDA10Zi-CrossLinQ
Crosstalk Measurements	DDA10Zi-CrossLinQ
Multi-Lane Serial Data Analysis LinQ	LM10Zi-SDAIII-LinQ
Framework, Eye and Jitter Measurements	SDA10Zi-LinQ
	DDA10Zi-LinQ
Single-Lane Serial Data Analysis	LM10Zi-SDAIII-Crosstalk
Framework, Eye, Jitter, Noise and	SDA10Zi-Crosstalk
Crosstalk Measurements	DDA10Zi-Crosstalk
Single-Lane Serial Data Analysis Framework,	LM10Zi-SDAIII
Eye and Jitter Measurements	
PAM4 Eye, Jitter and Noise Analysis	LM10ZI-PAM4

Signal Integrity Toolkits

Advanced De-embedding, Emulation and	LM10Zi-VIRTUALPROBE
Virtual Probing Toolkit	
Signal Integrity Toolkit - Channel & Fixture	LM10Zi-EYEDRII
De-embedding/Emulation, Tx/Rx Equalization	
Bundle - EyeDrII and VirtualProbe Toolkits	LM10Zi-EYEDRII-VP
Cable De-embed Option	LM10Zi-CBL-DE-EMBED

Modulated Signal Analysis

VectorLinQ - Flexible Vector Signal Analysis for	LM10Zi-VECTORLINQ
electrical signals (RF and baseband I-Q)	
Optical-LinQ - Coherent Optical Modulation	LM8Zi-OPTICAL-LINQ
Analysis	

Serial Data Compliance

CONTRACT CON	
QualiPHY Enabled 10GBase-KR Software Option	QPHY-10GBase-KR
QualiPHY Enabled 10GBase-T Software Option.	QPHY-10GBase-T
QualiPHY Enabled LPDDR2 Software Option	QPHY-LPDDR2
QualiPHY Enabled DDR3 Software Option	QPHY-DDR3
QualiPHY Enabled DDR4 Software Option	QPHY DDR4
QualiPHY Enabled DisplayPort Software Option	QPHY-DisplayPort
QualiPHY Enabled Embedded DisplayPort Software Option	on QPHY-eDP
QualiPHY Enabled HDMI 1.4 and HDMI 2 Software Option	QPHY-HDMI2 [†]
QualiPHY Enabled PCle 3.0 Software Option	QPHY-PCle3
QualiPHY Enabled PCle Gen1 Software Option	QPHY-PCle
QualiPHY Enabled SATA Software Option	QPHY-SATA-TSG-RSG
QualiPHY Enabled SAS-2 Software Option	QPHY-SAS2
QualiPHY Enabled SAS3 Software Option	QPHY-SAS3
QualiPHY Enabled SFI Software Option	QPHY-SFI
QualiPHY Enabled SuperSpeed USB Transmitter/	QPHY-USB3-Tx-Rx
Receiver Compliance Software Option	
QualiPHY Enabled USB3.1 Compliance Tx-Rx	QPHY-USB3.1-Tx-Rx
Software Option	

[†]TF-HDMI-3.3V-QUADPAK required.

PCI Express, SuperSpeed USB (USB 3.0) and SATA Complete Hardware/Software Test Solutions are available. Consult Factory.

Product Description

Product Code

Serial Data Test Fixtures

HDMI 50 Ω Pull-Up Terminator	TF-HDMI-3.3V
HDMI Pull-Up Terminator Quad Pack	TF-HDMI-3.3V-QUADPAK
SATA 1.5 Gb/s, 3.0 Gb/s and 6.0 Gb/s	TF-SATA-C
Compliance Test Fixture	
SATA 1.5 Gb/s, 3.0 Gb/s and 6.0 Gb/s	TF-SATA-C-KIT
Compliance Test Fixture Measure Kit	
SuperSpeed USB Compliance Test Fixture	TF-USB3
100 ps Rise Time Filter	RISE-TIME-FILTER-100PS
150 ps Rise Time Filter	RISE-TIME-FILTER-150PS
20 dB SMA Attenuators	20DB-SMA-ATTENUATOR

Product Code

Serial Data Triggers and Decoders	
600 Mb/s to 14.1 Gb/s 80-bit NRZ, 8b/10b and 64b/66b Serial Trigger. Also includes 8b/10b and 64b/66b Decode.	LM10ZI-14GBIT-80B-SYMBOL-TD
600 Mb/s to 6.5 Gb/s 80-bit NRZ, 8b/10b, 64b/66b Serial Trigger. Also includes 8b/10b and 64b/66b Decode.	LM10ZI-6GBIT-80B-SYMBOL-TD
64b/66b Decode Annotation Option	LM10Zi-64b66b D
8b/10b Decode Annotation Option	LM10Zi-8B10B D
CAN Decode	LM10Zi-CANBUS D
CAN FD Decode Option	LM10Zi-CAN FDbus D
ENET Decode Option	LM10Zi-ENETbus D
Ethernet 10G Decode Option	LM10Zi-ENET10Gbus D
PCI Express Decode Annotation Option	LM10Zi-PCIEbus D
USB 3.0 Decode Annotation Option	LM10Zi-USB3bus D
USB 2.0 Decode Annotation Option	LM10Zi-USB2bus D
USB2-HSIC Decode Option	LM10Zi-USB2-HSICbus D
SATA Decode Annotation Option	LM10Zi-SATAbus D
SAS Decode Annotation Option	LM10Zi-SASbus D
Fibre Channel Decode Annotation Option	LM10Zi-FCbus D
D-PHY Decode Option	LM10Zi-DPHYbus D
DigRF 3G Decode Option	LM10Zi-DigRF3Gbus D
DigRF v4 Decode Option	LM10Zi-DIGRFv4bus D
Audiobus and Decode Option for I ² S, LJ, RJ, and TDM	LM10Zi-Audiobus D
Audiobus, Decode, and Graph Option for I ² S, LJ, RJ, and TDM	LM10Zi-Audiobus DG
Manchester Decode Option	LM10Zi-Manchesterbus D
MIPI D-PHY Decode Annotation Option	LM10Zi-DPHYbus D
MIPI D-PHY Decode and Physical Layer Tes	st Option LM10Zi-DPHYbus DP
MIPI M-PHY Decode Annotation Option	LM10Zi-MPHYbus D
MIPI M-PHY Decode Annotation and Physic Test Option	cal Layer LM10Zi-MPHYbus DP
MIPI UniPro Protocol Decode Option	LM10Zi-UNIPRObus D
SpaceWire Decode Option	LM10Zi-SpaceWirebus D
I ² C Bus and Decode Option	LM10Zi-I2Cbus D
SPI Bus and Decode Option	LM10Zi-SPIbus D
LIN and Decode Option	LM10Zi-LINbus D
UART and RS-232 and Decode Option	LM10Zi-UART-RS232bus D
FlexRay and Decode Option	LM10Zi-FlexRaybus D
FlexRay, Decode, and	LM10Zi-FlexRaybus DP
Physical Layer Test Option CAN and Decode Option	1 M107: OANIb
CAN, Decode and Measure/Graph Option	LM10Zi-CANbus D
MIL-STD-1553 Decode Option	LM10Zi-CANbus DM LM10Zi-1553 D
ARINC 429 Symbolic Decode Option	LM10Zi-ARINC429bus DSymbolic
PROTObus MAG Serial Debug Toolkit	LM10Zi-PROTObus MAG
Decode Annotation and Protocol Analyzer	LM10ZI-PROTOBUS MAG LM10Zi-ProtoSync
Synchronization Software Option	LIVITUZI-PTOLOSYTIC
Decode Annotation and Protocol Analyzer Synchronization Software + Bit Tracer Option	LM10Zi-ProtoSync-BT
SENT Decode Option	LM10Zi-SENTbus D

ORDERING INFORMATION

General Purpose and Application Specific Software Options

Spectrum Analysis Option	LM10Zi-SPECTRUM
Digital Filter Software Package	LM10Zi-DFP2
Serial Data Mask Software Package	LM10Zi-SDM
Disk Drive Measurements Software Package	LM10Zi-DDM2
Disk Drive Analyzer Software Package	LM10Zi-DDA
Advanced Optical Recording Measurement Package	LM10Zi-AORM
EMC Pulse Parameter Software Package	LM10Zi-EMC
Clock Jitter Analysis with Four Views Software Package	LM10Zi-JITKIT

High Speed Output Accessories

Product Description

High-speed PCIe Gen 1 x4 Digitizer Output	LSIB-2
PCI Express x1 Express Card Host Interface for	LSIB-HOSTCARD
Laptop Express Card Slot	
PCI Express x1 Host Interface Board for Desktop PC	LSIB-HOSTBOARD
PCI Express x4 3-meter Cable	LSIB-CABLE-3M
with x4 Cable Connectors Included	
PCI Express x4 7-meter Cable	LSIB-CABLE-7M
with x4 Cable Connectors Included	

Miscellaneous

MCM-Zi-RACKMOUNT
LM10Zi-ACQMOD-RACKMOUNT
MCM-Zi-SOFTCASE
LM10Zi-ACQMOD-SOFTCASE

Probes and Probe Accessories

Product Description

Product Code

Flobes and Flobe Accessories	
WaveLink 13 GHz, 2.0 Vp-p Differential Probe System	D1305-A-PS
WaveLink 16 GHz, 2.0 Vp-p Differential Probe System	D1605-A-PS
WaveLink 20 GHz, 2.0 Vp-p Differential Probe System	D2005-A-PS
WaveLink 25 GHz, 2.0 Vp-p Differential Probe System	D2505-A-PS
Optical-to-Electrical Converter, DC to 9.5 GHz, 785 to 1550 nm	OE695G
2.92mm to ProLink Adapter with probe power and communications pass through	L2.92A-PLINK
2.92mm to ProBus Adapter with probe power and communications pass through	L2.92A-PBUS
200 MHz, 3.5 pF, 1 MΩ Active Differential Probe, ±20 V	ZD200††
500 MHz, 1.0 pF Active Differential Probe, ±8 V	ZD500††
1 GHz, 1.0 pF Active Differential Probe, ±8 V	ZD1000††
1.5 GHz, 1.0 pF Active Differential Probe, ±8 V	ZD1500††
2.5 GHz, 0.9 pF, 1 MΩ High Impedance Active Probe	ZS2500††
4 GHz, 0.6 pF, 1 M Ω High Impedance Active Probe	ZS4000††
WaveLink 4 GHz, 2.5 Vp-p Differential Probe System	D410-PS††
WaveLink 4 GHz, 5 Vp-p Differential Probe System	D420-PS††
WaveLink 6 GHz, 2.5 Vp-p Differential Probe System	D610-PS**
WaveLink 6 GHz, 5 Vp-p Differential Probe System	D620-PS**
WaveLink 8 GHz 3.5 Vp-p Differential Probe System	D830-PS**
WaveLink 10 GHz 3.5Vp-p Differential Probe System	D1030-PS**
WaveLink 13 GHz 3.5Vp-p Differential Probe System	D1330-PS**
WaveLink 6 GHz Differential Amplifier Module with Adjustable Tip	D600A-AT*
WaveLink 3 GHz Differential Amplifier Module with Adjustable Tip	D300A-AT†
WaveLink ProLink Platform/Cable Assembly (4 – 6 GHz)	WL-PLink-CASE**
WaveLink ProBus Platform/Cable Assembly (4 GHz)	WL-PBus-CASE ^{††}
SMA/SMP Lead Set for Dxx30 Probes	Dxx30-SMA-SMP Leads

Product Code

A variety of other active voltage and current probes are also available. Consult Teledyne LeCroy for more information.

Customer Service

Teledyne LeCroy oscilloscopes and probes are designed, built, and tested to ensure high reliability. In the unlikely event you experience difficulties, our digital oscilloscopes are fully warranted for three years and our probes are warranted for one year.

This warranty includes:

- No charge for return shipping
- Long-term 7-year support
- Upgrade to latest software at no charge



1-800-5-LeCroy teledynelecroy.com Local sales offices are located throughout the world. Visit our website to find the most convenient location.

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^{*} For a complete probe, order a WL-PLink-CASE Platform/Cable Assembly with the Adjustable Tip Module.

**Requires purchase and use of L2.92A-PLINK

† For a complete probe, order a WL-PBUS-CASE Platform/Cable Assembly

with the Adjustable Tip Module

^{††} Requires purchase and use of L2.92A-PBUS